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(54) Title (EN): SCREENING METHOD FOR CELLS PRODUCING SPECIFIC ANTIGEN-SPECIFIC ANTIBODY

(54) Title (FR): PROCÉDÉ DE CRIBLAGE POUR CELLULES PRODUISANT UN ANTICORPS SPÉCIFIQUE D'UN ANTIGÈNE SPÉCIFIQUE

(54) Title (JA): 特定抗原特異的抗体を産生する細胞のスクリーニング方法

(57) Abstract:

(EN): The present invention addresses the problem of providing a method for efficiently screening culture supernatant including cells that produce a specific antigen-specific antibody from a culture supernatant of cells that produce human antibodies. The present invention provides a method for screening culture supernatant including cells that produce a specific antigen-specific antibody from a culture supernatant of cells that produce human antibodies, the method involving using antibody-dependent cytotoxic activity as an indicator, wherein the method comprises selecting culture supernatant that satisfies prescribed conditions defined in the specification as the culture supernatant including cells that produce a specific antigen-specific antibody.

(FR): La présente invention aborde le problème consistant à fournir un procédé de criblage efficace de surnageant de culture comprenant des cellules qui produisent un anticorps spécifique d'un antigène spécifique à partir d'un surnageant de culture de cellules qui produisent des anticorps humains. La présente invention concerne un procédé de criblage de surnageant de culture comprenant des cellules qui produisent un anticorps spécifique d'un antigène spécifique à partir d'un surnageant de culture de cellules qui produisent des anticorps humains, le procédé impliquant l'utilisation d'une activité cytotoxique dépendante d'anticorps en tant qu'indicateur, le procédé comprenant la sélection d'un surnageant de culture qui satisfait à des conditions prescrites définies

dans la spécification en tant que surnageant de culture comprenant des cellules qui produisent un anticorps spécifique d'un antigène spécifique.

(JA): 本発明の課題は、ヒト抗体を産生する細胞の培養上清から、特定抗原特異的抗体を産生する細胞を含む培養上清を効率的にスクリーニングする方法を提供することである。本発明によれば、ヒト抗体を産生する細胞の培養上清から、抗体依存性細胞障害活性を指標として、特定抗原特異的抗体を産生する細胞を含む培養上清をスクリーニングする方法であって、明細書に規定する所定の条件を満たす培養上清を、特定抗原特異的抗体を産生する細胞を含む培養上清として選択する方法が提供される。

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